Teaching digital RT-level self-test using a Java applet
Devadze, Sergei; **Jutman, Artur**; **Sudnitsõn, Aleksander**; **Ubar, Raimund-Johannes**; Wuttke, Heinz-Dietrich 20th IEEE NORCHIP Conference : Copenhagen, Denmark, November 11-12, 2002 2002 / p. 322-328 : ill

Testability guided hierarchical test generation with decision diagrams
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